TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2962

Chopper Regulator, DC-DC Converter and Motor Drive Applications

Unit: mm

• 4 V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & \vdots\ R_{DS}\ (ON)=0.5\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & \vdots\ |Y_{fs}|=1.2\ S\ (typ.) \\ \bullet & Low\ leakage\ current & \vdots\ I_{DSS}=100\ \mu A\ (max)\ (V_{DS}=100\ V) \\ \bullet & Enhancement-mode & \vdots\ V_{th}=0.8\sim2.0\ V\ (V_{DS}=10\ V,\ I_{D}=1\ mA) \end{array}$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	100	V	
Drain-gate voltage (Ro	_{SS} = 20 kΩ)	V_{DGR}	100	V	
Gate-source voltage		V_{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	1	Α	
	Pulse (Note 1)	I _{DP}	3	Α	
Drain power dissipation	ı	P_{D}	0.9	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	137	mJ	
Avalanche current		I _{AR}	1	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	0.09	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	

2.2 max $0.75 \, \text{max}$ 1.0 max 10.5 min 0.8 max 0.6 max 1.27 2.54 1 2 3 1.SOURCE 2.DRAIN 3.GATE **JEDEC** TO-92MOD JEITA TOSHIBA 2-5J1C

Weight: 0.36 (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R _{th (ch-a)}	138	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 221 mH, R_G = 25 Ω , I_{AR} = 1 A

Note 3: Repetitive rating; Pulse width limited by maximum channel temperature.

This transistor is an electrostatic sensitive device.

Please handle with caution.

Electrical Characteristics (Ta = 25°C)

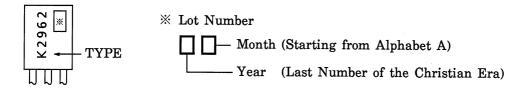
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Charac	cteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	ırrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	100	_	_	V
Gate threshold v	oltage/	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V
Drain-source ON resistance		R _{DS (ON)}	V _{GS} = 4 V, I _D = 0.5 A	_	0.65	0.95	Ω
			V _{GS} = 10 V, I _D = 0.5 A	_	0.5	0.7	32
Forward transfe	r admittance	Y _{fs}	V _{DS} = 10 V, I _D = 0.5 A	0.6	1.2	_	S
Input capacitano	e	C _{iss}			140	_	pF
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	20	_	
Output capacitance		Coss			45	_	1
Switching time	Rise time	t _r	$V_{GS} \xrightarrow[OV]{I_{D} = 0.5A} \circ V_{OUT}$ $R_{L} = 100 \Omega$ $V_{DD} = 50 V$	_	8	_	
	Turn-on time	t _{on}		_	13	_	ne
	Fall time	t _f		_	45		ns ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\mathbf{w}} = 10 \mu s$	_	175	_	
Total gate charge (gate-source plus gate-drain)		Qg			6.3		
Gate-source charge		Q _{gs}	$V_{DD} \approx 80 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 1 \text{ A}$		4.3	_	nC
Gate-drain ("miller") Charge		Q _{gd}			2	_	

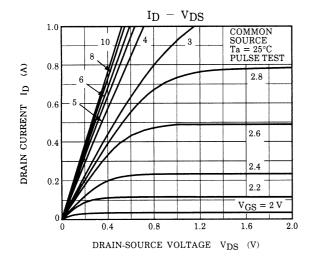
Source-Drain Ratings and Characteristics (Ta = 25°C)

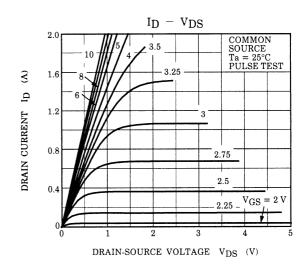
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	1	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	3	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 1 A, V _{GS} = 0 V	_	_	-1.5	V
Reverse recovery time	t _{rr}	I _{DR} = 1 A, V _{GS} = 0 V, dI _{DR} / dt = 50 A / μs	_	80	_	ns
Reverse recovery charge	Q _{rr}	- 1 Λ, VGS – 0 V, αιDR / αι – 30 Α / μs	_	140	_	nC

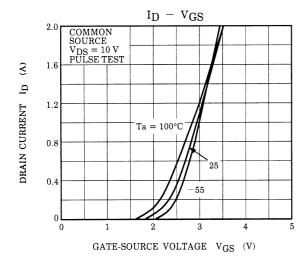
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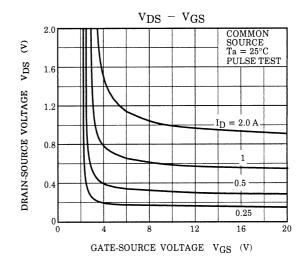


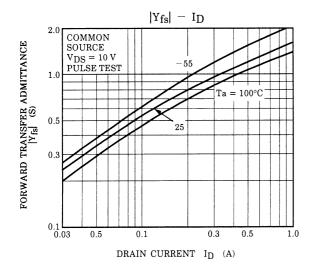
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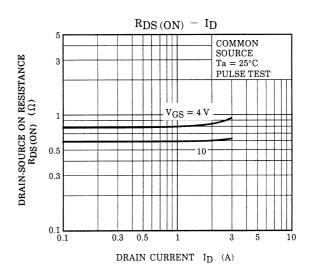


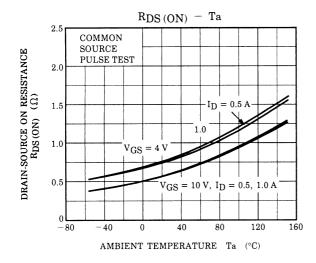


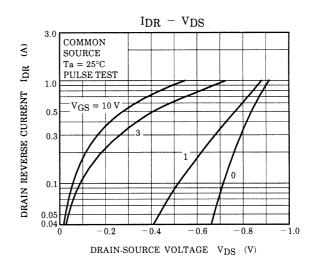


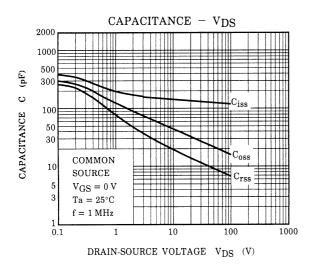


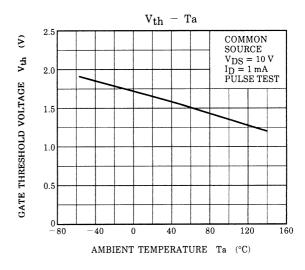


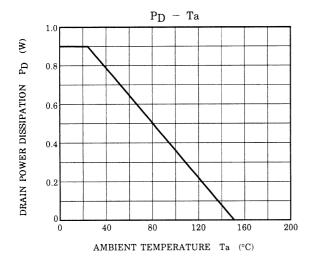


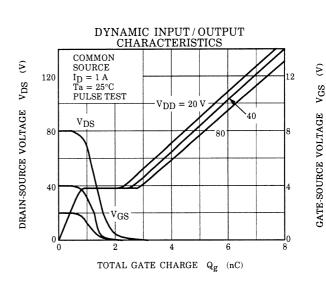




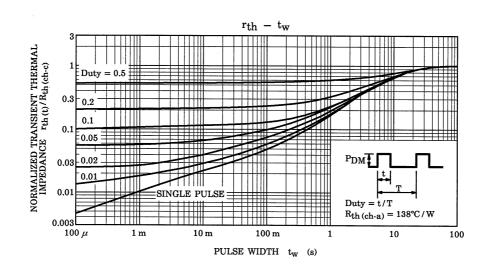


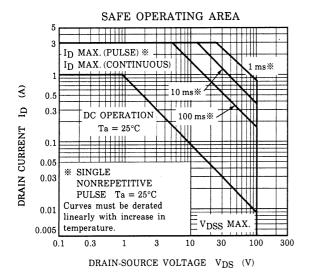


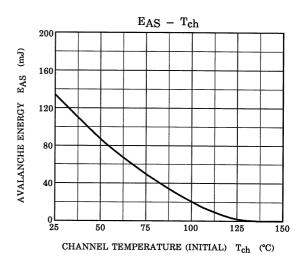


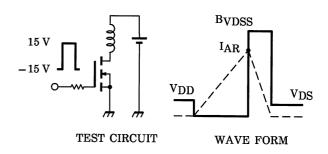


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$$\begin{aligned} &RG = 25~\Omega \\ &V_{DD} = 25~V,~L = 221~mH \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - V_{DD}} \right)$$

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